

Testing has never been so simple

3030 Bench Top

BENCHTOP MULTI-FUNCTION BOARD TESTER



Benchtop-Size Low Cost Tester

Hi-Speed In Circuit Test & Open Pin Scan

Automatic Test Program Generation

USB Connection to PC/Notebook

Ready to find process faults & structural defects

3030 Bench Top

3030 Bench Top is the benchtop size In-Circuit tester, with a large test capability and a small, lab-bench footprint. It can perform In-Circuit test and Open Pin Scan and is able to economically find process faults and structural defects.

Smart and intuitive, 3030 BT can be used without any test knowledge: **Leonardo** operating system **automatically generates and debugs** the test program, while a clear interface brings an **unskilled user** to get a stable production-ready test program in a **few clicks**.

Desktop computer or notebook: connected through **USB interface**, the 3030 BT can work with any computer and is **ready to test**. Additionally, 3030 BT can control any **remote receiver**, for full compatibility with existing fixtures.

Equipped with the same **high performance instrumentation** of SPEA 3030 series, the **3030 BT** guarantees **top level performance at entry level cost**. Furthermore, it can be installed in a **19-inch cabinet**, composing a multi-function test equipment that can grow according to the future needs.

With 3030 BT you do not worry about test. Just test.



Easy to Use

The operating system **Leonardo** quickly **generates** and **automatically debugs** the

test program, without requiring any knowledge. In few simple steps brings the user from data import to **production** test. Desktop computer or notebook can be easily connected through USB.



Small 19" Footprint

3030 BT has been conceived to provide a low-cost but powerful testing solution inside a lab-

bench footprint. The two front handles provide **easy carry** and **quick removal**, making **3030 BT** the perfect portable tester.



Test Program Transportability

3030 BT is equipped with an **internal CPU**. In this way the test program is **resident** in the internal processor and **runs independently** from PC timing. The **Test Program Transportability** is guaranteed: if the PC is changed, no tuning or re-debug of the test program is required.



Modular Architecture

The **modular architecture** of **3030 BT** allows to build your own configurable multi-function

tester. With its **4U 19-inch frame** it can be easily used on the **workbench**, but also **mounted** inside a standard rack case, composing a **multi-function test equipment** according to your needs.

Leonardo, Easy, Fast, Self-programming



- No need for test engineer or expert technician to develop and debug the test program
- Automatic test program generation in 1/2 hour
- Automatic debug & tuning
- Minimized application development costs: automatic generation of the file for fixture drilling and wiring
- Automatic CAD data recognition & import
- - 50% test program generation time compared to previous generation
- Automatic execution of **Built in Self Test** (BIST) to perform functional test in remarkable reduced time
- User-friendly intuitive graphic interface

Performance has never cost so little



Forget field return

3030 BT has been designed to help electronics manufacturers boost their **product quality**. By executing various test techniques with its high-performance instrumentation and stimuli, 3030 BT can **reliably find faults** undetectable by functional testers and standard ICT tester.



Cost-effective Per-Pin Architecture

Each 3030 BT channel is **configurable by test program.** Every nail can be used to perform any kind of test. This instrument/receiver **1:1 ratio** guarantees several benefits: faster test generation, easy ECO management, full flexibility.



Designed to last

State-of-art mechanics. Cable-less connections. 16-bit instrumentation. 8-wire measurements. PC-Independent Architecture. Everything has been designed to guarantee a reliable test at the lowest cost - even after **years of intensive use** - with an always **up-to-date equipment**.

Test Capabilities

With its Full In-Circuit Test, 3030 BT can easily and quickly find any process fault: short circuits and open circuits, incorrect component insertion, wrong value components, diodes, transistors or ICs incorrect orientation.

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Open Pin Scan finds **structural defects** such wrong polarity, polarized capacitors backwards, incorrectly mounted connectors, RF capacitor

presence (stray capacitors).

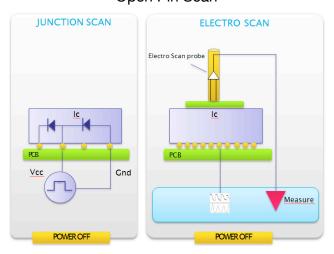
Analyze & optimize your process

QSoft is the **control software** developed by SPEA to **monitor**, **analyze** and **optimize** the production process.

- Integrated **data collection** from manual and automatic station
- Real time production monitoring and analysis
- Immediate report generation
- Repair station automator



Open Pin Scan



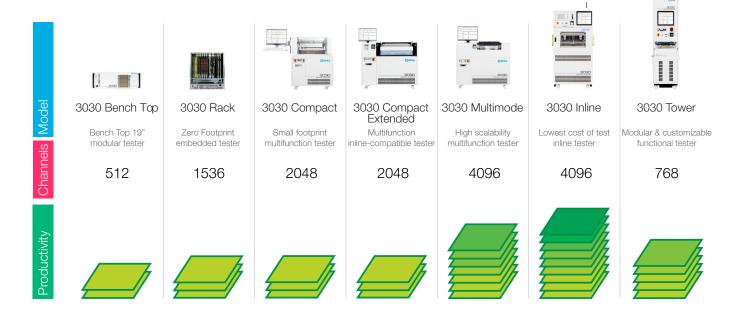
Two vector-less test techniques detect **open pins** and other process defects in **easy** and **fast way**

Easy control of any receiver



3030 BT can easily control one or two levels receivers

3030 - Product Range



3030 Bench Top - Specifications

Main Characteristic

| Test Core | |
|-----------------------------------|--------------------|
| Configuration - Core x Channels | 1x512 |
| Analog channels - Characteristics | 100V, 1A |
| Manual Loading Receiver | |
| Actuation | Pneumatic - Manual |
| Interface | |
| Connectors | Yes |
| Environment Requirements | |
| Transport temperature range | -25°C ÷ +55°C |
| Environmental temperature range | 15°C ÷ 32°C |
| Measurement temperature range | 15°C ÷ 32°C |
| Humidity | ≥20% ÷ ≤70% |
| System Specification | |
| Body main dimensions (L x W x H) | 466x483x177 mm |

Measure Capability

| Resistance | |
|-----------------------|--------------------------|
| Range | $1m\Omega \div 1G\Omega$ |
| Inductance | |
| Range | 1μH ÷ 1H |
| Capacitance | |
| Range | 0.5pF ÷ 1F |
| Test Type | |
| Electrical test | |
| ICT - In Circuit Test | Yes |
| Open Pin Scan | Yes |
| Open / Short | Yes |
| | |
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